



Very Low Power 4-Output PCIe Clock Generator With On-chip Termination

Features

- 1.8V supply voltage
- Crystal/CMOS input: 25 MHz
- 4 differential low power HCSL outputs with on-chip termination
- Individual output enable
- Reference CMOS output
- Programmable Slew rate and output amplitude for each output
- Differential outputs blocked until PLL is locked
- Selectable 0%, -0.25% or -0.5% spread on differential outputs
- Strapping pins or SMBus for configuration;
- 3.3V tolerant SMBus interface support
- Very low jitter outputs
 - Differential cycle-to-cycle jitter <50ps
 - Differential output-to-output skew <50ps
 - PCIe Gen1/Gen2/Gen3/Gen4 compliant
 - CMOS REFOUT phase jitter is < 1.5ps RMS
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2) •
- Halogen and Antimony Free. "Green" Device (Note 3)
- For automotive applications requiring specific change control (i.e. parts qualified to AEC-Q100/101/200, PPAP capable, and manufactured in IATF 16949 certified facilities), please contact us or your local Diodes representative.

https://www.diodes.com/quality/product-definitions/

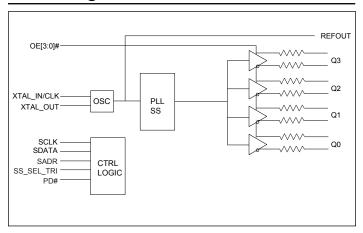
- Packaging (Pb-free & Green):
 - 32-lead 5×5mm TQFN

Description

The PI6CG18401 is an 4-output very low power PCIe Gen1/ Gen2/Gen3/Gen4 clock generator. It uses 25MHz crystal or CMOS reference as an input to generate the 100MHz low power differential HCSL outputs with on-chip terminations. The on-chip termination can save 16 external resistors and make layout easier. An additional buffered reference output is provided to serve as a low noise reference for other circuitry.

It uses Diodes proprietary PLL design to achieve very low jitter that meets PCIe Gen1/Gen2/Gen3/Gen4 requirements. It also provides various options such as different slew rate and amplitude through strapping pins or SMBUS so that users can configure the device easily to get the optimized performance for their individual boards. The device also supports selectable spreadspectrum options to reduce EMI for various applications.

Block Diagram



Notes:

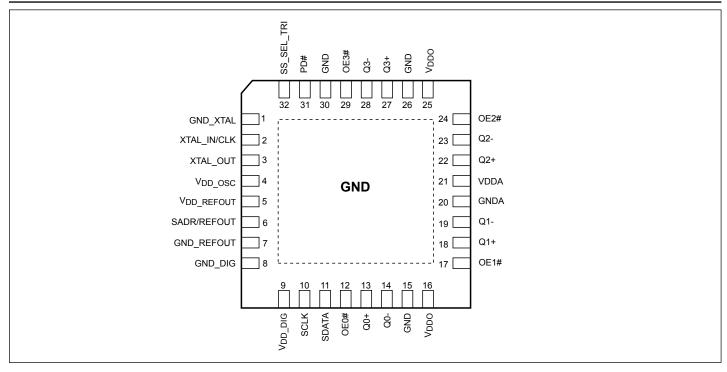
^{1.} No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.

^{2.} See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free. 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.





Pin Configuration



Pin Description

Pin #	Pin Name Type		ре	Description
1	GND_XTAL	Power		Ground for oscillator circuit
2	XTAL_IN/CLK	Input		Crystal input or CMOS reference input
3	XTAL_OUT	Output		Crystal output
4	V _{DD} _OSC	Power		Power supply for oscillator circuitry, nominal 1.8V
5	V _{DD} _REFOUT	Power		Power supply for buffered CMOS output
6	SADR/REFOUT	Input/ Output	CMOS	Latch to select SMBus Address or 1.8V LVCMOS REFOUT. This pin has internal pull-down.
7	GND_REFOUT	Power		Ground for REFOUT
8	GND_DIG	Power		Ground for digital circuitry
9	V _{DD} _DIG	Power		Power supply for digital circuitry, nominal 1.8V
10	SCLK	Input	CMOS	SMBUS clock input, 3.3V tolerant
11	SDATA	Input/ Output	CMOS	SMBUS Data line, 3.3V tolerant
12	OE0#	Input	CMOS	Active low input for enabling Q0 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
13	Q0+	Output	HCSL	Differential true clock output
14	Q0-	Output	HCSL	Differential complementary clock output
15, 26, 30	GND	Power		Ground





Pin Description Cont.

Pin #	Pin Name	Ту	ре	Description
16, 25	V _{DDO}	Power		Power supply for differential outputs
17	OE1#	Input	CMOS	Active low input for enabling Q1 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
18	Q1+	Output	HCSL	Differential true clock output
19	Q1-	Output	HCSL	Differential complementary clock output
20	GNDA	Power		Ground for analog circuitry
21	V _{DDA}	Power		Power supply for analog circuitry
22	Q2+	Output	HCSL	Differential true clock output
23	Q2-	Output	HCSL	Differential complementary clock output
24	OE2#	Input	CMOS	Active low input for enabling Q2 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
27	Q3+	Output	HCSL	Differential true clock output
28	Q3-	Output	HCSL	Differential complementary clock output
29	OE3#	Input	CMOS	Active low input for enabling Q3 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
31	PD#	Input	CMOS	Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode, subsequent high assertions exit Power Down Mode. This pin has internal pull-up resistor.
32	SS_SEL_TRI	Input	Tri-level	Latched select input to select spread spectrum amount at initial power up $1 = -0.5\%$ spread, M = -0.25%, 0 = Spread Off

SMBus Address Selection Table

	SADR	Address	+Read/Write Bit
State of SADD on first and lighting of DD#	0	1101000	Х
State of SADR on first application of PD#	1	1101010	Х

Power Management Table

PD#	SMBus OE bit	OEn#	Qn+	Qn-	REFOUT
0	Х	Х	Low	Low	HiZ
1	1	0	Running	Running	Running
1	1	1	Low	Low	Low
1	0	Х	Low	Low	Low





Maximum Ratings

(Above which useful life may be impaired. For user guidelines, not tested.)
Storage Temperature65°C to +150°C	Note:
Supply Voltage to Ground Potential, VDDxx0.5V to +2.5V	Stresse
Input Voltage –0.5V to $V_{DD+0.5V}$, not exceed 2.5V	cause p functio
SMBus, Input High Voltage 3.6V	above t
ESD Protection (HBM)	is not in
Max Junction Temperature+125°C	extend

sses greater than those listed under MAXIMUM RATINGS may e permanent damage to the device. This is a stress rating only and tional operation of the device at these or any other conditions re those indicated in the operational sections of this specification t implied. Exposure to absolute maximum rating conditions for nded periods may affect reliability.

Operating Conditions

Temperature = T_A ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{DD} , V _{DDA} , V _{DD} _OSC, V _{DD} _RE- FOUT, V _{DD} _DIG	Power Supply Voltage		1.7	1.8	1.9	V
V _{DDO}	Output Power Supply Voltage		1.7	1.8	1.9	V
I _{DDA}	Analog Power Supply Current	All outputs active @100MHz		6	9	mA
I _{DD}	Power Supply Current	All V_{DD} , except V_{DDA} and V_{DDO} , All outputs active @100MHz		4	6	mA
I _{DDO}	Power Supply Current for Outputs	All outputs active @100MHz		21	25	mA
I _{DDA_WL}	Analog Power Supply Wake-on- LAN ⁽¹⁾ Current	Q outputs off, REF output running		0.4	1	mA
I _{DD_WL}	Power Supply Wake-on-LAN ⁽¹⁾ Current	All V_{DD} , except V_{DDA} and V_{DDO} , Q outputs off, REF output running		1	2	mA
I _{DDO_WL}	Power Supply Wake-on-LAN ⁽¹⁾ Current for Outputs	Q outputs off, REF output running		0.04	0.1	mA
I _{DDA_PD}	Analog Power Supply Power Down ⁽²⁾ Current	All outputs off		0.4	1	mA
I _{DD_PD}	Power Supply Power Down ⁽²⁾ Current	All outputs off		0.6	1	mA
I _{DDO_PD}	Power Supply Current Power Down ⁽²⁾ for Outputs	All outputs off		0.0005	0.1	mA
T _A	Ambient Temperature	Industrial grade	-40		85	°C

Note:

1. Wake-on-LAN mode: PD# = '0' Byte 3, bit 5 = '1'

2. Power down mode: PD# = '0' Byte 3, bit 5 = '0'





Input Electrical Characteristics

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
R _{pu}	Internal pull up resistance			120		KΩ
R _{dn}	Internal pull down resistance			120		KΩ
C _{XTAL}	Internal capacitance on X_IN and X_OUT pins			5		pF
L _{PIN}	Pin inductance				7	nH

Crystal Characteristic

Parameters	Description	Min.	Тур	Max.	Units
OSCmode	Mode of Oscillation	F	undamenta	al	
FREQ	Frequency		25		MHz
ESR ⁽¹⁾	Equivalent Series Resistance			50	Ω
Cload	Load Capacitance		8		pF
Cshunt	Shunt Capacitance			7	pF
	Drive Level			300	uW

Note:

1. ESR value is dependent upon frequency of oscillation

SMBus Electrical Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{DDSMB}	Nominal bus voltage		1.7		3.6	V
		SMBus, $V_{DDSMB} = 3.3V$	2.1		3.6	
V _{IHSMB}	SMBus Input High Voltage	SMBus, V _{DDSMB} < 3.3V	0.65 V _{DDSMB}			V
17		SMBus, V _{DDSMB} = 3.3V			0.6	v
V _{ILSMB}	SMBus Input Low Voltage	SMBus, V _{DDSMB} < 3.3V			0.6	
I _{SMBSINK}	SMBus sink current	SMBus, at V _{OLSMB}	4			mA
VOLSMB	SMBus Output Low Voltage	SMBus, at I _{SMBSINK}			0.4	V
f _{MAXSMB}	SMBus operating frequency	Maximum frequency			400	kHz
t _{RMSB}	SMBus rise time	(Max V _{IL} - 0.15) to (Min V _{IH} + 0.15)			1000	ns
t _{FMSB}	SMBus fall time	(Min $\mathrm{V_{IH}}$ + 0.15) to (Max $\mathrm{V_{IL}}$ - 0.15)			300	ns

Spread Spectrum Characteristic

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f _{MOD}	SS Modulation Frequency	Triangular modulation	30	31.6	33	kHz





LVCMOS DC Electrical Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V _{IH}	Input High Voltage	Single-ended inputs, except SMBus	0.75 V _{DD}		V _{DD} +0.3	V
V _{IM}	Input Mid Voltage	SS_SEL_TRI	$0.4 V_{DD}$	$0.5 V_{DD}$	$0.6V_{\rm DD}$	V
V _{IL}	Input Low Voltage	Single-ended inputs, except SMBus	-0.3		0.25 V _{DD}	V
I _{IH}	Input High Current	Single-ended inputs, $V_{IN} = V_{DD}$			20	μA
I _{IL}	Input Low Current	Single-ended inputs, $V_{IN} = 0V$	-20			μA
I _{IH}	Input High Current	Single-ended inputs with pull up / pull down resistor, $V_{\rm IN}$ = $V_{\rm DD}$			220	μA
I _{IL}	Input Low Current	Single-ended inputs with pull up / pull down resistor, $V_{IN} = 0V$	-220			μA
V _{OH}	Output High Voltage	REFOUT, except SMBus; I _{OH} = -2mA	V _{DD} -0.45			V
V _{OL}	Output Low Voltage	REFOUT, except SMBus; I _{OH} = 2mA			0.45	V
R _{OUT}	CMOS Output impedance			20		Ω
C _{IN}	Input Capacitance		1.5		5	pF

LVCMOS AC Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f _{INPUT}	Input Frequency	XTAL_IN/CLK	23	25	27	MHz
t _{RIN}	Input rise time	Single-ended inputs			5	ns
t _{FIN}	Input fall time	Single-ended inputs			5	ns
t _{STAB}	Clock stabilization	From Power-Up and after input clock stabi- lization or de-assertion of PD# to 1st clock		0.6	1.8	ms
t _{OELAT}	Output enable latency	Q start after OE# assertion Q stop after OE# deassertion	1		3	clocks
t _{PDLAT}	PD# de-assertion	Differential outputs enable after PD# de- assertion		20	300	us
t _{PERIOD}	REFOUT clock period	REFOUT, assume input is at 25MHz		40		ns
f _{ACC}	REFOUT frequency ac- curacy ⁽¹⁾	REFOUT, long term accuracy to input		0		ppm
		Byte 3 = 1F, 20% to 80% of V_{DDREF}	0.6	1	1.8	V/ns
		Byte 3 = 5F, 20% to 80% of V _{DDREF}	0.75	1.6	2.5	V/ns
t _{SLEW}	REFOUT slew rate ⁽¹⁾	Byte 3 = 9F, 20% to 80% of V _{DDREF}	0.85	2.0	3.0	V/ns
		Byte 3 = DF, 20% to 80% of V _{DDREF}	1.0	2.1	27 5 5 1.8 3 300 1.8 1.8 2.5	V/ns





Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
t _{DC}	REFOUT Duty Cycle ⁽¹⁾	$V_{\rm T} = V_{\rm DD}$ /2 V, driven by a Xtal	45	50	55	%
t _{DCDIS}	REFOUT Duty Cycle Distor- tion	$V_{\rm T}$ = $V_{\rm DD}$ /2 V, driven by an external source	0	2	4	%
t _{JITCC}	REFOUT cycle-cycle jitter	$V_{\rm T} = V_{\rm DD}$ /2 V, driven by a Xtal		70	130	ps
t _{JITPH}	REFOUT phase jitter	12kHz to 5MHz, RMS, driven by a Xtal		0.2	0.5	ps
1	Nation flags	1kHz offset, driven by a Xtal		-130	-105	dBc
t _{JITN}	Noise floor	10kHz offset to Nyquist, driven by a Xtal		-140	-120	dBc

IVCMOS AC Characteristics Cont

Note:

1. Guaranteed by design and characterization, not 100% tested in production

HCSL Output Characteristics

Temperature = T_A; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
V _{OH}	Output Voltage High ⁽¹⁾	Statistical measurement on single-ended	660	784	850	mV
VOL	Output Voltage Low ⁽¹⁾	signal using oscilloscope math function	-150		150	mV
VOMAX	Output Voltage Maximum ⁽¹⁾	Measurement on single ended signal using		816	1150	mV
V _{OMIN}	Output Voltage Minimum ⁽¹⁾	absolute value	-300	-15		mV
VOSWING	Output Swing Voltage ^(1,2,3)	Scope averaging off	300	1551		mV
V _{OC}	Output Cross Voltage ^(1,2,4)		250	400	550	mV
DV _{OC}	V _{OC} Magnitude Change ^(1,2,5)			14	140	mV

Note:

1. At default SMBUS amplitude settings

2. Guaranteed by design and characterization, not 100% tested in production

3. Measured from differential waveform

4. This one is defined as voltage where Q+ = Q- measured on a component test board and only applied to the differential rising edge

5. The total variation of all Vcross measurements in any particular system. This is a subset of Vcross_min/max allowed.

HCSL Output AC Characteristics

Temperature = T_A ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
f _{OUT}	Output Frequency			100		MHz
	Slew rate ^(1,2,3)	Scope averaging on fast setting	2	3.1	4.4	V/ns
t _{RF}	Slew rate(1,2,5)	Scope averaging on slow setting	1.1	2.0	3.0	V/ns
Dt _{RF}	Slew rate matching ^(1,2,4)	Scope averaging on		3		%
t _{DC}	Duty Cycle ^(1,2)	Measured differentially, PLL Mode	45	50	55	%
t _{SKEW}	Output Skew ^(1,2)	Averaging on, $V_T = 50\%$		34	50	ps
tj _{c-c}	Cycle to cycle jitter ^(1,2)			14	50	ps
t _{STARTUP}	Start up time				10	ms
t _{LOCK}	PLL lock time				20	ms





HCSL Output AC Characteristics Cont.

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
		PCIe Gen 1	20	25	86	ps
		PCIe Gen 2 Low Band, 10kHz < f < 1.5MHz	0.8	0.9	3.0	ps
		PCIe Gen 2 High Band, 1.5MHz < f < Ny- quist (50MHz)	1.5	1.6	3.1	ps
tj _{PHASE}	Integrated phase jitter (RMS) (1,5,6)	PCIe Gen 3 Common Clock Architecture (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.4	0.5	1.0	ps
		PCIe Gen 3 Separate Reference No Spread (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.4	0.5	0.7	ps
		PCIe Gen 4 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.3	0.37	0.5	ps

Note:

1. Guaranteed by design and characterization, not 100% tested in production

2. Measured from differential waveform

3. Slew rate is measured through the Vswing voltage range centered around differential 0V, within +/-150mV window

4. It is measured using a +/-75mV window centered on the average cross point

5. See http://www.pcisig.com for complete specs

6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of 10^{-12}

Differential Output Clock Periods - Spread Spectrum Disabled^(1, 2)

			Mea	surement Wir	ndow			
Center	1 clock	1 us	0.1 s	0.1 s	0.1 s	1 us	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns

Differential Output Clock Periods - Spread Spectrum Enabled^(1, 2)

			Mea	surement Wir	ndow			
Center	1 clock	1 us	0.1 s	0.1 s	0.1 s	1 us	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns

Note:

1. Guaranteed by design and characterization, not 100% tested in production

2. All long term accuracy and clock period specifications are guaranteed assuming REF is trimmed to 25.00MHz





SMBus Serial Data Interface

PI6CG18401 is a slave only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below.

Read and write block transfers can be stopped after any complete byte transfer.

Address Assignment

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	0	SADR	0	1/0

Note: SMBus address is latched on SADR pin

How to Write

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack	 Data Byte (N+X-1)	Ack	Stop bit

How to Read

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Repeat Start bit	Address	R(1)	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack

8 bits	1 bit	1 bit
Data Byte	NAck	Stop bit
(N+X-1)	MACK	Stop bit





Byte 0: Output Enable Register⁽¹⁾

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	Q3_OE	Q3 output enable	RW	1	Low/Low	Enabled
2	Q2_OE	Q2 output enable	RW	1	Low/Low	Enabled
1	Q1_OE	Q1 output enable	RW	1	Low/Low	Enabled
0	Q0_OE	Q0 output enable	RW	1	Low/Low	Enabled

Note:

1. A low on these bits will override the OE# pins and force the differential outputs to Low/Low states

Byte 1: SS Readback and Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	SSENRB1	SS Enable Readback Bit1	R	Latch	'00' for SS_SEL	_TRI = '0',
6	SSENRB0	SS Enable Readback Bit0	R	Latch	'01' for SS_SEL_ '11' for SS_SEL_	- ´
5	SSEN_SWCTR	Enable SW control of SS	RW	0	Values in B1[7:6] control SS amount	Values in B1[4:3] control SS amount
4	SSENSW1	SS enable SW control Bit1	RW ⁽¹⁾	0	'00' = SS off, '01	' = -0.25% SS,
3	SSENSW0	SS enable SW control Bit0	RW ⁽¹⁾	0	'10' = Reserved,	'11' = -0.5% SS
2	Reserved			1		
1	Amplitude1	Control output orgality do	RW	1	'00' = 0.6V, '01' =	= 0.7V, '10' =
0	Amplitude0	Control output amplitude	RW	0	0.8V, '11' = 0.9V	

Note:

1. B1[5] must be set to a 1 for these bits to have any effect on the part.





Byte 2: Differential Output Slew Rate Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	SLEWRATECTR_Q3	Control slew rate of Q3	RW	1	Slow setting	Fast setting
2	SLEWRATECTR_Q2	Control slew rate of Q2	RW	1	Slow setting	Fast setting
1	SLEWRATECTR_Q1	Control slew rate of Q1	RW	1	Slow setting	Fast setting
0	SLEWRATECTR_Q0	Control slew rate of Q0	RW	1	Slow setting	Fast setting

Byte 3: REF Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7			RW	0	'00' = 0.9V/ns '0	1' = 1.3V/ns,
6	REFSLEWRATE	Slew rate control for REF	RW	1	'10' = 1.6V/ns, '1	1' = 1.8V/ns
5	REF_PDSTATE	Wake-on-Lan enable for REF	RW	0	REF = 'Low'	REF = run- ning
4	REF_OE	Output enable for REF	RW	1	REF = "Low'	REF = run- ning
3	Reserved			1		
2	Reserved			1		
1	Reserved			1		
0	Reserved			1		

Byte 4: Reserved

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:0	Reserved					





Byte 5: Revision and Vendor ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	RID3		R	0	rev = 0000	
6	RID2	Revision ID	R	0		
5	RID1		R	0		
4	RID0		R	0		
3	PVID3		R	0		
2	PVID2		R	0	D: 1 0011	
1	PVID1	-	R	1	Diodes = 0011	
0	PVID0		R	1		

Byte 6: Device Type/Device ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	DTYPE1	Derivation	R	0	'00' = CG, '01' =	ZDB,
6	DTYPE0	Device type	R	0	'10' = Reserve, '	11' = ZDB
5	DID5		R	0		
4	DID4	-	R	0		
3	DID3	Device ID	R	0	000100 him a ma	0411.04
2	DID2	Device ID	R	1	000100 binary,	04Hex
1	DID1		R	0		
0	DID0		R	0		

Byte 7: Byte Count Register

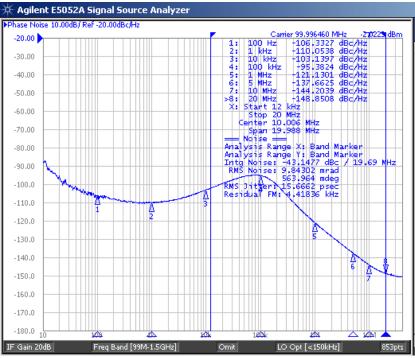
Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	BC4		RW	0	Writing to this register will configure how many bytes w	
3	BC3	-	RW	1		
2	BC2	Byte count programming	RW	0		
1	BC1		RW	0	be read back, de	efault is 8 bytes
0	BC0		RW	0		



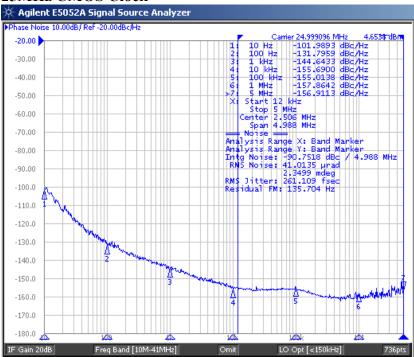


Plots

100MHz HCSL Clock



25MHz CMOS Clock







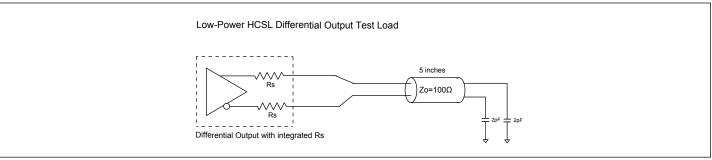


Figure 1. Low Power HCSL Test Circuit

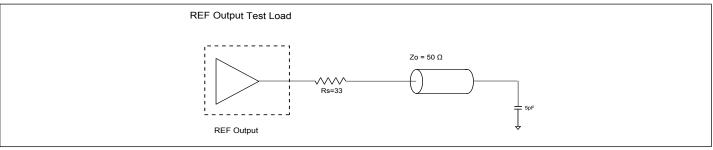


Figure 2. CMOS REF Test Circuit

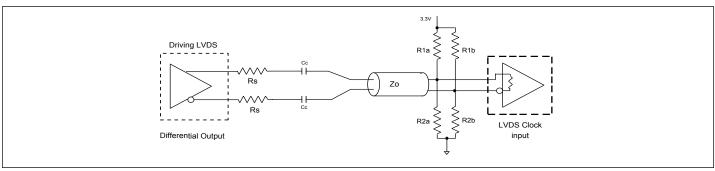


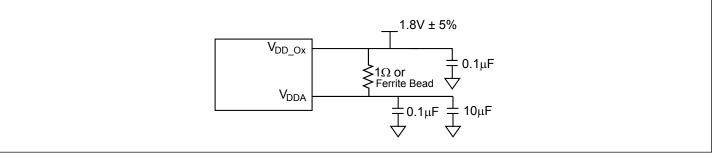
Figure 3. Differential Output driving LVDS

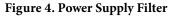
Alternate Differential Output Terminations

Component	Receiver with termination	Receiver without termination	Unit
R _{1a} , R _{1b}	10,000	140	Ω
R_{2a}, R_{2b}	5,600	75	Ω
C _C	0.1	0.1	μF
V _{CM}	1.2	1.2	V





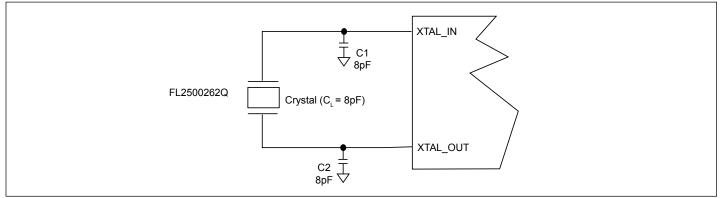




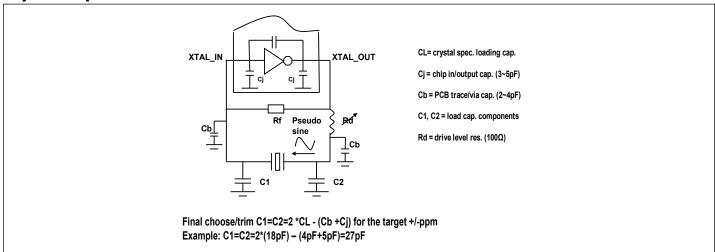
Crystal Circuit Connection

The following diagram shows PI6CG18401 crystal circuit connection with a parallel crystal. For the CL=8pF crystal, it is suggested to use C1=8pF, C2=8pF. C1 and C2 can be adjusted to fine tune to the target ppm of crystal oscillator according to different board layouts based on the following formular in the Crystal Capacitor Calculation diagram.

Crystal Oscillator Circuit



Crystal Capacitor Calculation





A Product Line of	
Diodes Incorporated	



Recommended Crystal Specification

Diodes recommends:

a) FL2500217, SMD 3.2x2.5(4P), 25MHz, CL=8pF, +/-20ppm, http://www.Diodes.com/pdf/datasheets/se/FL.pdf

Part Marking

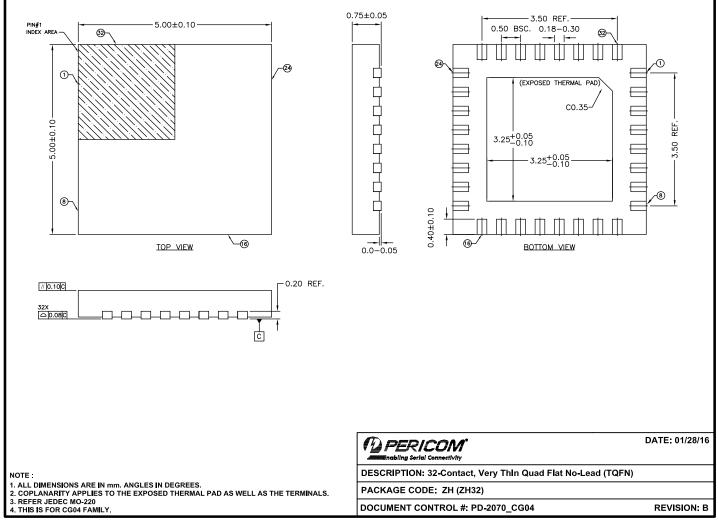
PI6C0 401Zł ZYYW o	HE_
Z: Die Re YY: Year WW: Wor 1st X: As 2nd X: Fa	kweek sembly Code





Packaging Mechanical

32-TQFN (ZH)



For latest package info.

 $please \ check: \ http://www.diodes.com/design/support/packaging/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/pericom-packaging/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-mechanicals-and-thermal-characteristics/pericom-packaging-packaging-pac$

Ordering Information

Ordering Code	Package Code	Package Description	Pin 1 Location
PI6CG18401ZHIEX	ZH	32-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Right Corner
PI6CG18401ZHIEX-13R	ZH	32-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Left Corner

Notes:

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.

2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free. 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

- 4. I = Industrial
- 5. E = Pb-free and Green
- 6. X suffix = Tape/Reel

7. For packaging detail, go to our website at: https://www.diodes.com/assets/MediaList-Attachments/Diodes-Package-Information.pdf





IMPORTANT NOTICE

DIODES INCORPORATED AND ITS SUBSIDIARIES ("DIODES") MAKE NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARDS 1. TO ANY INFORMATION CONTAINED IN THIS DOCUMENT, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY, FIT-NESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION).

2. The Information contained herein is for informational purpose only and is provided only to illustrate the operation of Diodes products described herein and application examples. Diodes does not assume any liability arising out of the application or use of this document or any product described herein. This document is intended for skilled and technically trained engineering customers and users who design with Diodes products. Diodes products may be used to facilitate safety-related applications; however, in all instances customers and users are responsible for (a) selecting the appropriate Diodes products for their applications, (b) evaluating the suitability of the Diodes products for their intended applications, (c) ensuring their applications, which incorporate Diodes products, comply the applicable legal and regulatory requirements as well as safety and functional-safety related standards, and (d) ensuring they design with appropriate safeguards (including testing, validation, quality control techniques, redundancy, malfunction prevention, and appropriate treatment for aging degradation) to minimize the risks associated with their applications.

3 Diodes assumes no liability for any application-related information, support, assistance or feedback that may be provided by Diodes from time to time. Any customer or user of this document or products described herein will assume all risks and liabilities associated with such use, and will hold Diodes and all companies whose products are represented herein or on Diodes' websites, harmless against all damages and liabilities.

Products described herein may be covered by one or more United States, international or foreign patents and pending patent applications. Product 4. names and markings noted herein may also be covered by one or more United States, international or foreign trademarks and trademark applications. Diodes does not convey any license under any of its intellectual property rights or the rights of any third parties (including third parties whose products and services may be described in this document or on Diodes' website) under this document.

5 Diodes products are provided subject to Diodes' Standard Terms and Conditions of Sale (https://www.diodes.com/about/company/terms-and-conditions/terms-and-conditions-of-sales/) or other applicable terms. This document does not alter or expand the applicable warranties provided by Diodes. Diodes does not warrant or accept any liability whatsoever in respect of any products purchased through unauthorized sales channel.

6. Diodes products and technology may not be used for or incorporated into any products or systems whose manufacture, use or sale is prohibited under any applicable laws and regulations. Should customers or users use Diodes products in contravention of any applicable laws or regulations, or for any unintended or unauthorized application, customers and users will (a) be solely responsible for any damages, losses or penalties arising in connection therewith or as a result thereof, and (b) indemnify and hold Diodes and its representatives and agents harmless against any and all claims, damages, expenses, and attorney fees arising out of, directly or indirectly, any claim relating to any noncompliance with the applicable laws and regulations, as well as any unintended or unauthorized application.

7 While efforts have been made to ensure the information contained in this document is accurate, complete and current, it may contain technical inaccuracies, omissions and typographical errors. Diodes does not warrant that information contained in this document is error-free and Diodes is under no obligation to update or otherwise correct this information. Notwithstanding the foregoing, Diodes reserves the right to make modifications, enhancements, improvements, corrections or other changes without further notice to this document and any product described herein. This document is written in English but may be translated into multiple languages for reference. Only the English version of this document is the final and determinative format released by Diodes.

Any unauthorized copying, modification, distribution, transmission, display or other use of this document (or any portion hereof) is prohibited. Diodes 8. assumes no responsibility for any losses incurred by the customers or users or any third parties arising from any such unauthorized use.

Copyright © 2022 Diodes Incorporated

www.diodes.com